, Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/796,090	TAKE, KEIJIRO
Examiner	Art Unit
IriH. Phan	2661

SEARCHED				
Class	Subclass	Date	Examiner	
370	320,335, 342,441, 479,203	11/30/2004	TP	
370	350,332	11/30/2004	TP	
370	508-510	11/30/2004	TP	
375	200	11/30/2004	TP	
Updated	search	6/17/2005	TP ·	
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH N (INCLUDING SEARC		)
	DATE	EXMR
EAST, IEEE, Internet searched	11/30/2004	TP
Consulted with Sam Phirin (Pri)	4/7/2005	TP
Updated search	6/17/2005	TP
Eat	12/20/05	Ba
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